

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10775242	KOYAMA ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Fujita, Katrina	2609

## SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

## SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
(382/112,162,167,254,276,282,305) text search only - see search history printouts	03/14/2007	KF
(345/581,589-591,593) text search only - see search history printouts	03/14/2007	KF
EAST text search - see search history printouts	03/15/2007	KF
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IEEE text search - see search history printouts	03/14/2007	KF
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Google Scholar text search - see search history printouts	03/19/2007	KF
Updated EAST search - see search history printouts	02/13/2008	KF
STIC search - see search history printouts	02/01/2008	KF
Updated EAST search - see search history printouts	09/08/2008	KF

## INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>

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Examiner.Art Unit 2624